
Conformance testing

Application Note 1280



**– an essential part of
SDH deployment**

Introduction

Testing SDH network elements (NEs) for compliance with the relevant standards is a complex and time-consuming application. It is, however, an essential part of building SDH-compliant networks.

Glossary

ADM	Add-drop multiplexer
AIS	Alarm indication signal
AU	Administrative unit
BIP	Bit interleaved parity
ETSI	European telecommunications standards institute
FERF	Far end receive failure
FEBE	Far end block error
HP	High-order path
ITU-T	International telecommunication union – telecommunication sector
LOF	Loss of frame
LOP	Loss of pointer
LOS	Loss of signal
LP	Low-order path
MS	Multiplexer section
NDF	New data flag
NE(s)	Network element(s)
OOF	Out of frame
RDI	Remote defect indication (previously known as FERF)
REI	Remote error indication (previously known as FEBE)
SDH	Synchronous digital hierarchy
STM-n	Synchronous transport module level 'n' (n = 1, 4, 16 or 64)
TU	Tributary unit

SDH conformance testing – the need for a standard

Since the mid 1980s, thousands of engineering-years of effort have been applied to the creation of today's SDH standards. The prize which justifies this staggering investment in the standardization process is "a telecommunications transmission network for the 21st century" – a system, based on SDH-compliant network elements (NEs), which is flexible, reliable, and efficient to operate and maintain.

From a network operator's point of view, the benefits promised by SDH technology are four-fold:

- Efficient management of network bandwidth.
- Extensive in-service performance monitoring.
- Dynamic network protection.
- Inter-operability of NEs from different vendors.

Realizing these benefits relies on the uniform implementation of a wide range of inter-linked functions within SDH equipment. Together, these functions fully describe the NE's functional operating characteristics. Verifying correct operation of these basic functions is therefore the first vital step in ensuring that new (or upgraded) SDH equipment delivers the promised operational benefits.

Current SDH standards (ITU-T G.Series and ETSI TM-1015) restrict themselves to describing, in detail, the required operating characteristics for compliant network elements. What they do not cover is an industry accepted method for verifying compliance. This lack of a 'conformance test' dimension to the standards leaves a fundamental question unanswered, namely: What constitutes SDH compliance?

Allowing each organization involved in SDH compliance testing to formulate its own answer will, without doubt, carry a significant cost. At best, the cost will be delays in deploying new generations of SDH NEs (or upgrades to those already deployed) due to test duplication. At worst, it will result in equipment which deviates from the standards being deployed, thereby risking network integrity.

To ensure that there is only one answer to the SDH compliance question will require the creation of a conformance test standard – a document which clearly defines 'what to test' and 'the method to use'. ETSI recognized this need, a fact clearly demonstrated by work currently in progress within working group 3 of the TM1 committee (TM1/WG3). This work is aimed at adding the necessary conformance test dimension to ETSI's draft TM-1015 SDH standards document.

Get it right first time !

What is conformance testing ?

The term 'conformance test' refers to the in-depth testing necessary to verify an NE's compliance with ITU-T and ETSI standards. This design verification application can be segmented into three broad categories:

- Functional testing (signal structure, operating characteristics).
- Network management protocol testing.
- Parametric testing (physical line signal characteristics).

Of these categories, 'functional testing' is the area which should be given priority when considering test standardization. This view is arrived at after evaluating each category against factors such as:

- Stability of standards.
- Scope for differing interpretations of current standards.
- How often testing is necessary.

Conformance testing is a costly undertaking, both in terms of time and capital investment necessary to perform the task. It is also a recurring application. These two facts emphasize the importance of adopting a test approach which is effective and efficient.

Successful conformance testing requires a solution which enables you to execute hundreds of complex tests, and obtain repeatable results in which you have full confidence. The size and recurring nature of the application requires that this is achieved in a way which minimizes test time. A solution which meets these requirements will consist of:

- Tests designed to rigorously verify all specified operating characteristics of an NE.
- High performance measurement hardware providing the real-time controls necessary to reliably generate complex test signals (eg, alarm and error sequences for threshold tests).
- A well defined and documented test procedure.
- An efficient method for executing sequences of tests (typically achieved through automation).

SDH functional tests

Testing an SDH NE for compliance with the standards entails detailed verification of its operation in the areas of:

- Alarm handling.
- Pointer processing.
- Protection switching.
- Overhead channels.
- Performance monitoring.
- Payload handling.
- Jitter and wander.

Many of these functional tests require the application of a single input stimulus and the monitoring of multiple output responses.

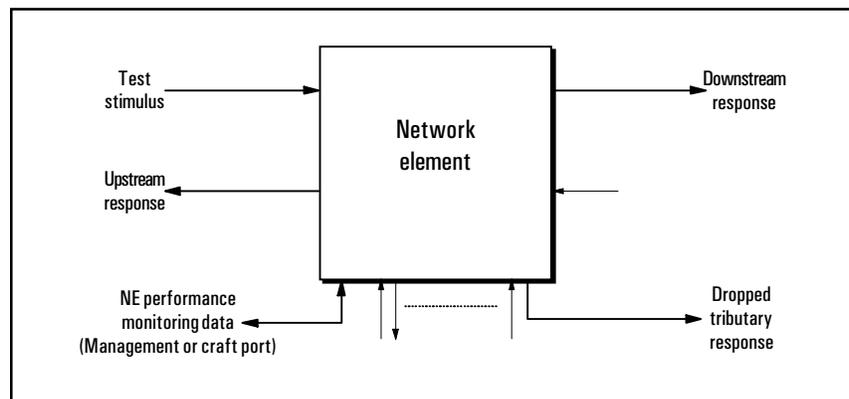


Figure 1. Connecting to network element under test

An example of this is testing an ADM's response to a received MS-AIS defect. On detecting this defect the ADM must:

- Transmit AU-AIS in all unterminated downstream paths.
- Transmit HP-RDI upstream in all terminated paths.
- Transmit AIS in all dropped tributaries.
- Transmit MS-RDI upstream.
- Record the MS-AIS defect in its internal performance monitoring.

When designing an SDH conformance test station and its associated test procedure, you must therefore make a decision on whether all responses are tested simultaneously or separately. The trade-off you will make is cost, in terms of measurement hardware, versus test time.

SDH alarm testing

SDH standards define a hierarchy of alarm conditions, covering defects detected at the:

- Physical transmission layer (LOS).
- Regenerator section termination (OOF, LOF).
- Multiplexer section termination (MS-AIS/RDI).
- High-order path access level (AU-LOP).
- High-order path termination (AU-AIS/HP-RDI).
- Low-order path access level (TU-LOP).
- Low-order path termination (TU-AIS/LP-RDI).

Full compliance testing of an NE's alarm handling entails verifying the alarm detection and de-activation thresholds, plus the appropriate responses (including internal performance monitoring). This must be done for each alarm supported by the NE.

To rigorously test an alarm detection/de-activation threshold, measurement hardware capable of generating a precise three-stage alarm on/off sequence is required. This sequence consists of:

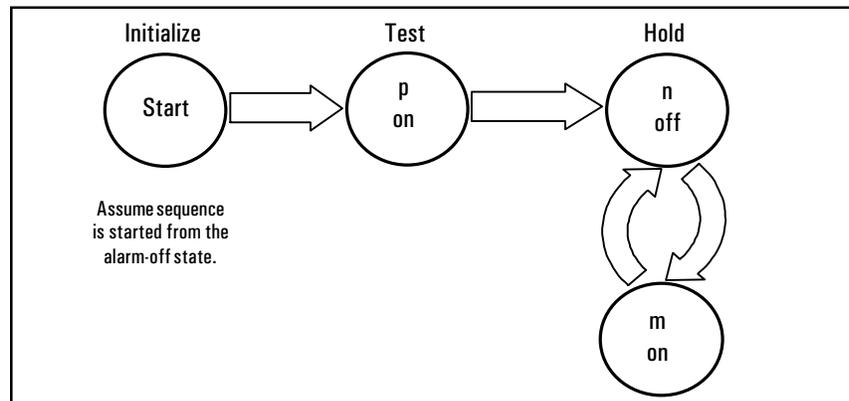


Figure 2. Testing alarm detection and de-activation thresholds

- A user-definable starting state (alarm on or off).
- The test condition – a single burst of the alarm on or off (opposite polarity to starting state). The duration of this burst is programmed to be equal to or just below the threshold level under test.
- A repeating on/off sequence designed to hold the NE in the alarm state it enters as a result of the test condition. On and off durations are separately programmed to be below the expected alarm detection and de-activation thresholds.

This three-stage sequence supports rigorous alarm threshold testing by ensuring the NE has only one opportunity to detect the test condition.

As a practical illustration, consider how the above sequence is used to test MS-AIS. ETSI TM-1015 specifies that an NE must enter the MS-AIS state on receiving three to five consecutive frames containing the MS-AIS signal. Exiting the MS-AIS state must occur on receiving three to five consecutive frames which do not contain the MS-AIS signal.

Testing pointer generators and interpreters

Pointers perform a critical role in the error-free transmission of payload data (subscriber data) through an SDH network. They also enable individual payload channels to be simply inserted or extracted from a high-speed STM-n line signal (an example of this being the functionality provided by ADMs).

Thorough testing of an NE's compliance with the complex pointer generation and interpretation rules is an essential part of the SDH conformance test application. The pointer functions which require verification are:

- NE generates valid pointer structure (NDF, SS-bits, offset address).
- Error-free handling of pointer justifications (increment and decrement from all possible offsets).
- I and D bit majority voting.
- NDF operation.
- NDF majority voting.
- LOP entry and exit criteria.

The ability to perform this type of detailed testing requires measurement hardware capable of dynamically erroring the pointer associated with a mapped payload test pattern. With the exception of LOP tests, correct operation is verified by monitoring the payload test pattern for errors.

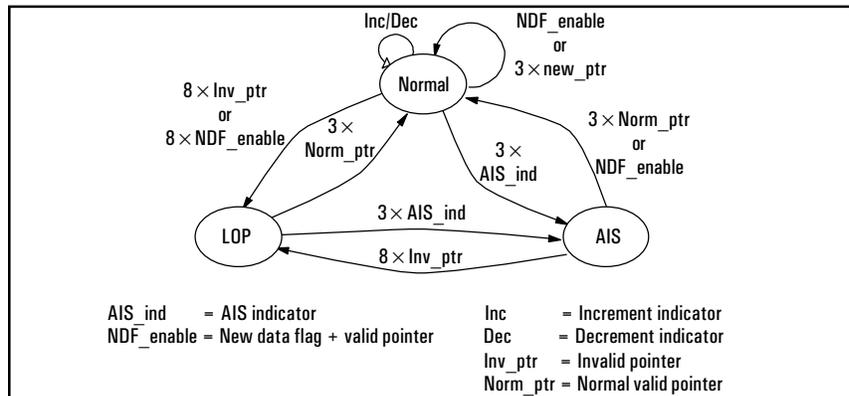


Figure 4. Pointer operation: ETSI TM-1015

The above clearly illustrates the complexity of the SDH pointer interpreter rules. Testing an NE for correct implementation of these rules requires measurement hardware capable of generating sequences of errored and valid pointers similar to that described for alarm threshold testing.

Testing an NE's performance monitoring functions

Another significant area for SDH conformance testing is verifying an NE's in-service performance monitoring functions, namely:

- Valid BIP generation.
- Correct BIP error detection.
- Upstream REI generation on detection of received B2/B3/BIP-2 errors.
- REI detection.
- Internal logging of errored seconds and severely error seconds information.

Performing this type of test requires measurement hardware capable of generating controlled errors in a selected BIP or REI channel. On the receive side the measurement hardware must provide BIP and REI error measurements.

Access to the NE's internal performance monitoring data is also necessary. This can be achieved via the NE's management system or, alternatively, using a local control terminal connected to the NE's craft port.

Conclusion

Testing SDH network elements for conformance with the standards is a costly and recurring application. It is, however, an essential part of building an SDH compliant network.

The costs associated with this application can be minimized through 'test standardization' coupled with 'test automation'. Adopting a solution based on these two principles will ensure your SDH conformance testing is both effective and efficient by providing:

- Repeatable testing.
- Simpler result interpretation.
- Improved ability to share result data with other conformance test groups.

For information on SDH conformance test solutions, contact your local Hewlett-Packard sales office.

Related HP literature

HP 75000 Series 90 Technical specifications 5964-9881E
modular telecom
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Tel: (81-426) 48-0722
Fax: (81-426) 48-1073

Latin America:

Hewlett-Packard
Latin American Region Headquarters
5200 Blue Lagoon Drive
9th Floor
Miami, Florida 33126
USA
(305) 267 4245/4220

Australia/New Zealand:

Hewlett-Packard Australia Ltd.
31-41 Joseph Street
Blackburn, Victoria 3130
Australia
131 347 ext. 2902

Asia Pacific:

Hewlett-Packard Asia Pacific Ltd.
17-21/F Shell Tower, Times Square
1 Matheson Street, Causeway Bay
Hong Kong
(852) 2599 7070

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